

**Notice of References Cited**

Application/Control No.

10/015,899

Applicant(s)/Patent Under

Reexamination

WATANABE ET AL.

Examiner

SATISH RAMPURIA

Art Unit

2191

Page 1 of 1

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**NON-PATENT DOCUMENTS**

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Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.